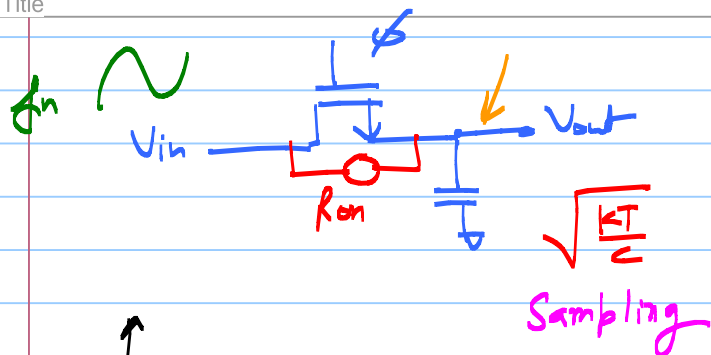


ECE 614 - Lecture 13

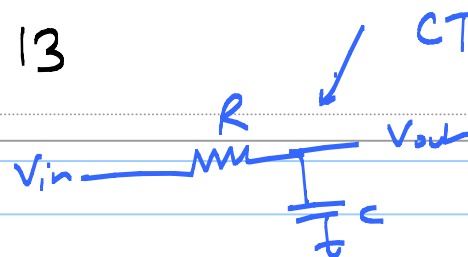
Note Title

10/16/2012



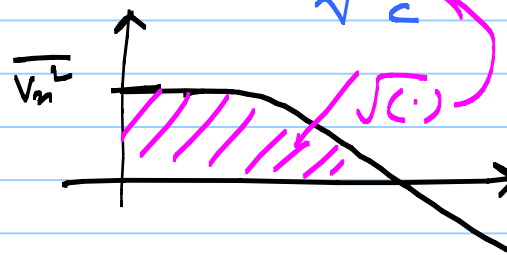
$$f_s \geq 2 BW$$

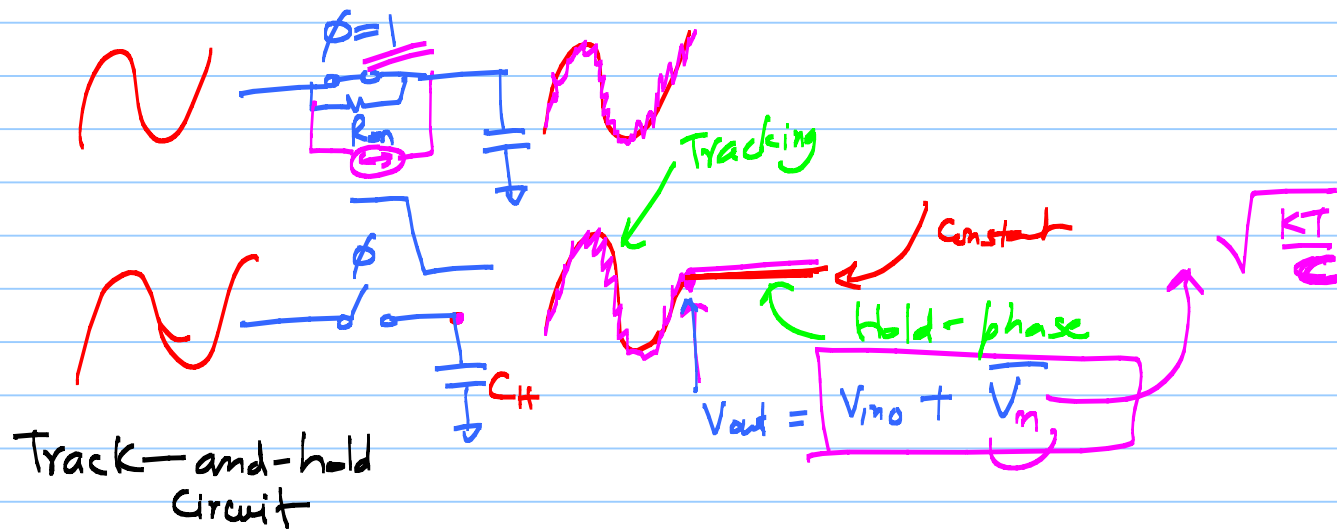
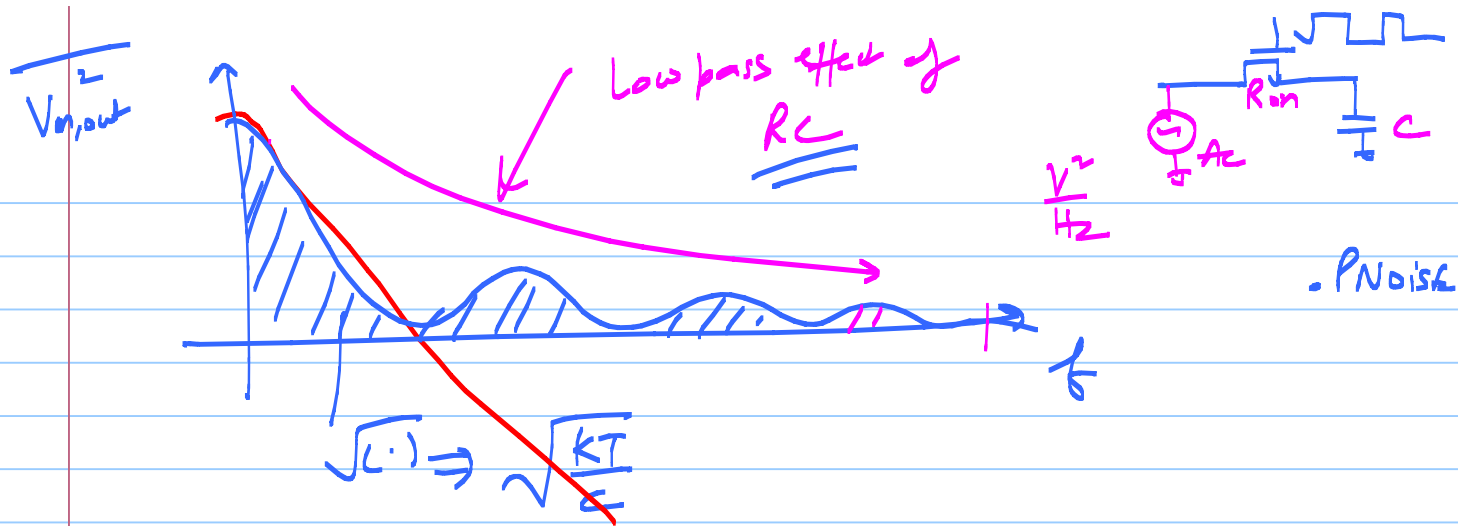
Nyquist Sampling Theorem

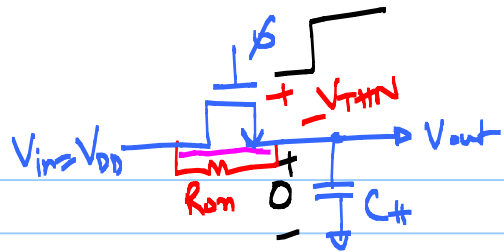


$$V_{noise,rms} = \sqrt{\int_0^{\infty} V_n^2(f) df}$$

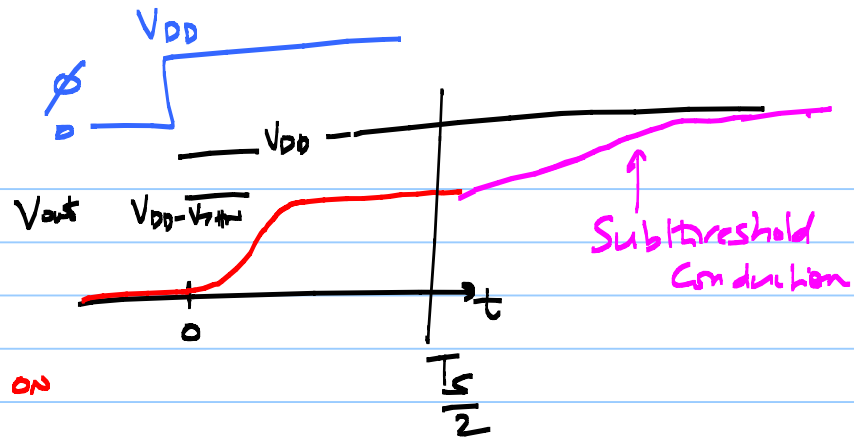
$$= \sqrt{\frac{kT}{2C}}$$

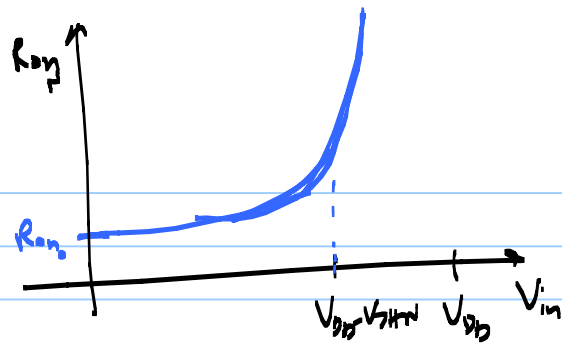






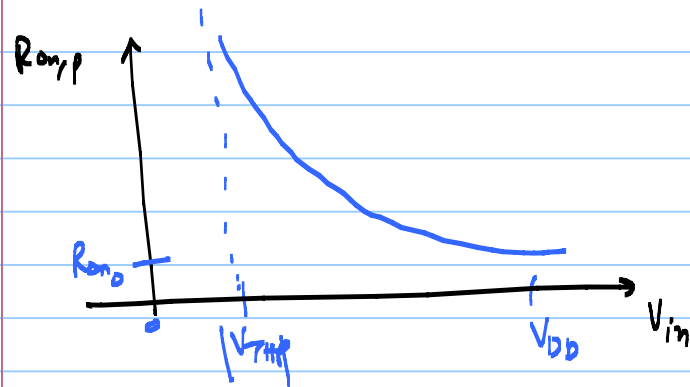
- Switch open $\rightarrow$ MOSFET is off
- Switch closed $\rightarrow$ MOSFET on



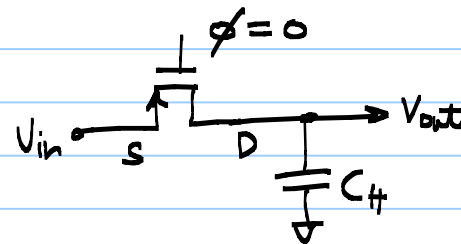


$$R_{on,n} = \frac{1}{\mu_n C_{ox} \frac{W}{L} (V_{DD} - V_{in} - V_{THN})}$$

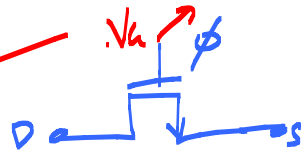
↑ Triode



$$R_{on,p} = \frac{1}{\mu_p C_{ox} \frac{W}{L} (V_{in} - |V_{THP}|)}$$



MOS
a good switch

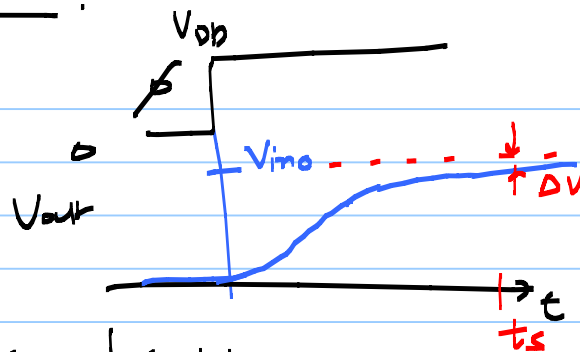
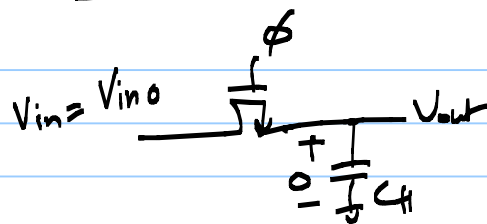


* D & S can interchange

* V_G is unhinged from V_D, V_S

* Can be ON without conducting
any dc current

Speed Considerations



⇒ speed spec must come from precision

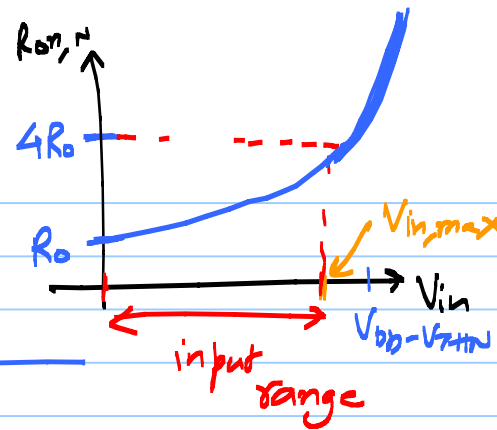
$$t_s < \frac{T_p}{2}$$

$$\tau = R_{on} \cdot C_{II}$$

$\downarrow$ Large $\frac{W}{L}$ $\downarrow$ small cap

$$R_{on} = f(V_{in})$$

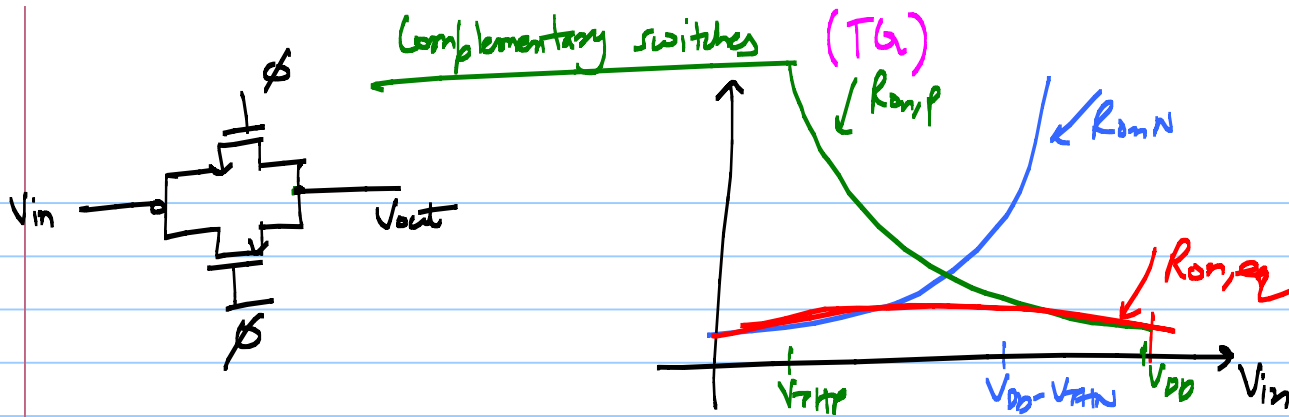
If we restrict R_{on} to a range of 4 to 1



$$\underbrace{\frac{1}{\mu_n C_{ox} \frac{W}{L} (V_{DD} - V_{in, max} - V_{THN})}}_{R_{on}(V_{in, max})} = \frac{4}{\underbrace{\mu_n C_{ox} \frac{W}{L} (V_{DD} - V_{THN})}_{4 \cdot R_{on}(*)}}$$

$$V_{in, max} = \frac{3}{4} (V_{DD} - V_{THN}) \approx \frac{V_{DD}}{2}$$

↑ Severe swing limitation

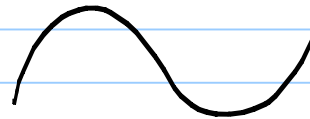
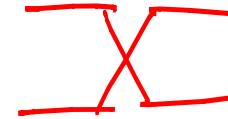
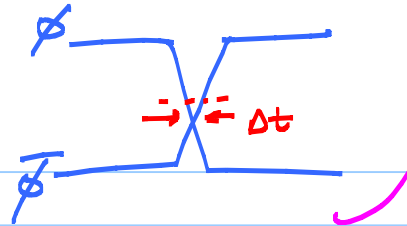
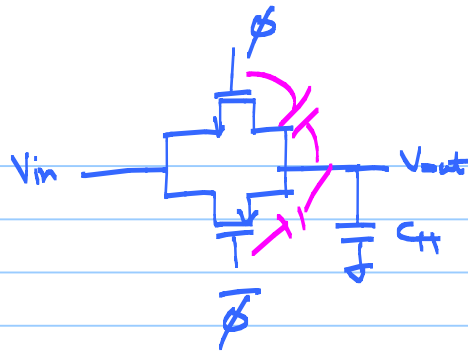


$$R_{on,eq} = R_{on,p} \parallel R_{on,n}$$

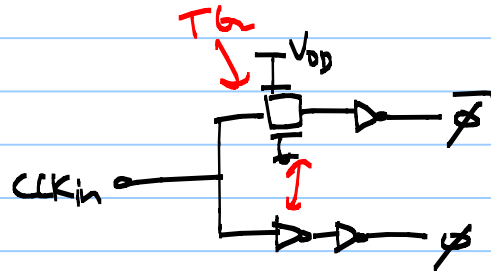
$$= \frac{1}{\mu_n C_{ox} \left(\frac{W}{L}\right)_n (V_{DD} - V_{THN}) - \underbrace{\left[\mu_n C_{ox} \left(\frac{W}{L}\right)_n - \mu_p C_{ox} \left(\frac{W}{L}\right)_p \right]}_{\substack{\downarrow \\ \approx 0}} V_{in} - \mu_p C_{ox} \left(\frac{W}{L}\right)_p |V_{THP}|}$$

$\nearrow f(V_{in})$
 $\searrow$
 $\nearrow f(V_{in})$

mostly independent of input level

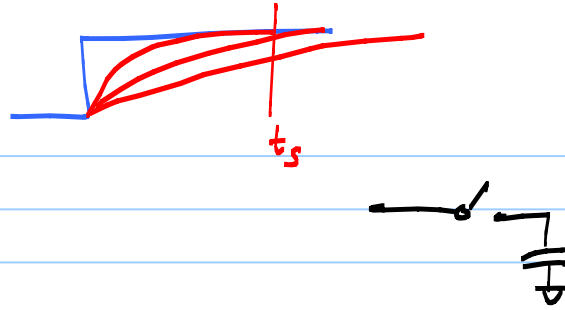


ideal value
distortion generated in the sampled value



Simple circuit

$$\tau = R_{on,eq} \cdot C_H$$



$$\frac{V_{out}}{V_{in_0}} = \left(1 - e^{-t/\tau}\right)$$

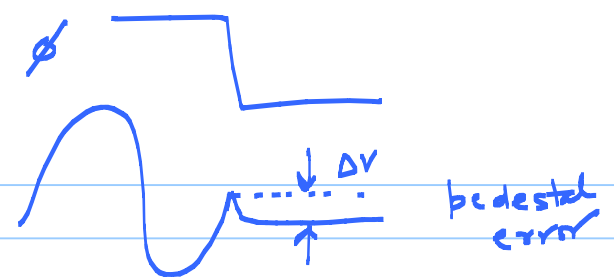
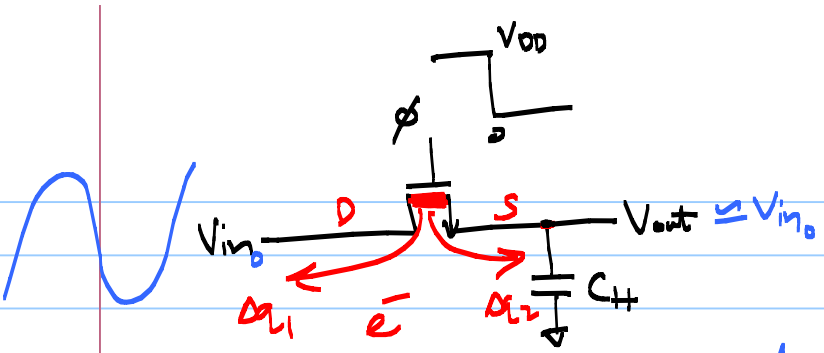
$$\Rightarrow V_{out} = (1 - \epsilon) V_{in_0}$$

$\uparrow$
 error

$$\Rightarrow \tau_s = \tau \ln(1/\epsilon)$$

Precision Consideration

- ① Channel "Charge injection"
- ② Clock feedthrough
- ③ $\frac{KI}{C}$ Noise $\left(\sqrt{\frac{KT}{C}}\right)$



Triode

→ $Q_{ch} = WL C_{ox} (V_{DD} - \underline{V_{in}} - \underline{V_{THN}})$

Total channel charge

$V_{THN} = \phi (\sqrt{2\phi_B + V_{in}} - \sqrt{2\phi_B})$

Assuming that $\frac{Q_{ch}}{2}$ is injected into C_H

$$\Delta V = - \frac{WL C_{ox} (V_{DD} - V_{in} - V_{THN})}{2 C_H} \quad (\text{negative})$$

$Q_{ch} \propto WL$
 $\propto \frac{1}{C_H}$

$V_{out} = ?$

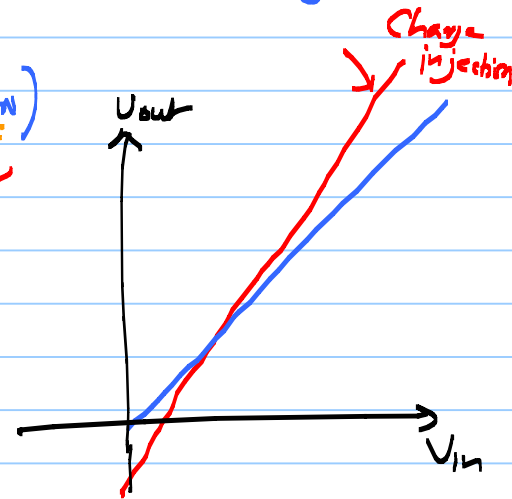
$$V_{out} = V_{in} - |\Delta V| \leftarrow \text{C.T. error}$$

$$\Rightarrow V_{out} = V_{in} - \frac{WL C_{ox} (V_{DD} - V_{in} - V_{THN})}{C_H}$$

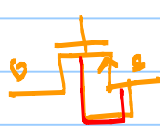
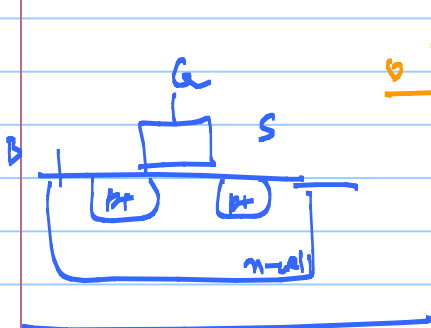
= "V_{in}" ideally

$$= \underbrace{V_{in} \left(1 + \frac{WL C_{ox}}{C_H} \right)}_{\text{gain} > 1} - \underbrace{\frac{WL C_{ox}}{C_H} (V_{DD} - V_{THN})}_{\text{DC offset}}$$

* all Q_{ch} is injected into C_H
 ↳ worst case analysis

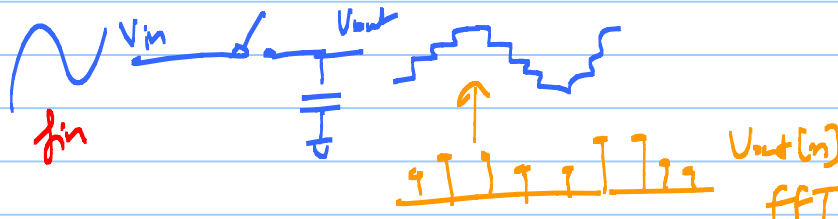


⇒ PMOS → D & S can interchange



Body-effect still exists

$$V_{out} = V_{in} \left(1 + \underbrace{\frac{WLC_{ox}}{C_H}}_{\text{gain error}} \right) + \underbrace{\gamma \frac{WLC_{ox}}{C_H} \sqrt{2\phi_B + V_{in}}}_{\text{non linearity due to body effect}} - \underbrace{\frac{WLC_{ox}}{C_H} (V_{DD} - V_{THNO} + \gamma \sqrt{2\phi_B})}_{\text{DC offset}}$$



$$(1+x)^{1/2} = 1 + a_1 x + a_2 x^2 + a_3 x^3 + \dots + \dots + \infty$$

